

# Bias Current Sources

- Applications
- Design objectives
  - Output resistance (& capacitance)
  - Voltage range ( $V_{\min}$ )
  - Accuracy
  - Noise
- Cascoding
- High-Swing Biasing



# Matching

- Systematic mismatch
  - $\Delta V_{DS}$
  - source resistance
- Random mismatch
  - $\Delta (W/L)$
  - $\Delta V_{TH}$
  - gradients



# Random Mismatch

- Model: (assume square-law)
 
$$I_{D1} = \frac{1}{2} \mu C_{ox} \left(\frac{W}{L}\right)_1 (V_{GS} - V_{TH1})^2$$

$$I_{D2} = \frac{1}{2} \mu C_{ox} \left(\frac{W}{L}\right)_2 (V_{GS} - V_{TH2})^2$$
- Mismatch:  $\Delta I_D, \Delta(W/L), \Delta V_{TH}$ 

$$\Delta I_D = I_{D1} - I_{D2} \quad I_D = 0.5(I_{D1} + I_{D2})$$

$$\Delta\left(\frac{W}{L}\right) = \left(\frac{W}{L}\right)_1 - \left(\frac{W}{L}\right)_2 \quad \left(\frac{W}{L}\right) = 0.5\left[\left(\frac{W}{L}\right)_1 + \left(\frac{W}{L}\right)_2\right]$$

$$\Delta V_{TH} = V_{TH1} - V_{TH2} \quad V_{TH} = 0.5(V_{TH1} + V_{TH2})$$
- Substitute:
 
$$\frac{\Delta I_D}{I_D} = \frac{\Delta\left(\frac{W}{L}\right)}{\left(\frac{W}{L}\right)} - \frac{1}{2} \frac{\Delta V_{TH}}{(V_{GS} - V_{TH})}$$
- → choose large  $V_{GS} - V_{TH}$  ( $V_{ov}$ )



# Mismatch Example

$$\sigma_{\frac{\Delta(W/L)}{(W/L)}} = 1\%$$

$$\sigma_{\Delta V_{TH}} = 3\text{mV}$$

$$V_{GS} - V_{TH} = 300\text{mV}$$

$$\sigma_{\frac{\Delta I_D}{I_D}}^2 = \sigma_{\frac{\Delta(W/L)}{(W/L)}}^2 + \frac{1}{4} \frac{\sigma_{\Delta V_{TH}}^2}{(V_{GS} - V_{TH})^2}$$

$$= (0.01)^2 + \left(\frac{3}{2 \times 300}\right)^2 = (100 + 25) \times 10^{-6}$$

$$= \underline{(1.1\%)^2}$$

- Represent mismatch as random quantities
- Variances (squares!) add ... like noise
- Use large  $V_{ov}$  (or degeneration) for good current mirror matching



# Yield

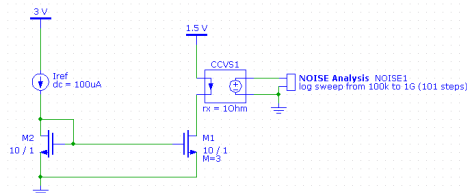
- Yield = fraction of good dies
- E.g. need  $\pm 2.2\%$  matching  
 $\sigma = 1.1\%$ ,  
 $k = 2.2 / 1.1 = 2$   
  
yield =  $0.954 = \underline{95.4\%}$
- Typical design goal:  
 $\pm 3\sigma$  ("6 $\sigma$ "), i.e.  $k=3$

k	Yield
0.2	0.159
0.4	0.311
0.6	0.451
0.8	0.576
1.0	0.683
1.2	0.766
1.4	0.838
1.6	0.890
1.8	0.928
2.0	0.954
2.2	0.972
2.4	0.984
2.6	0.991
2.8	0.995
3.0	0.997

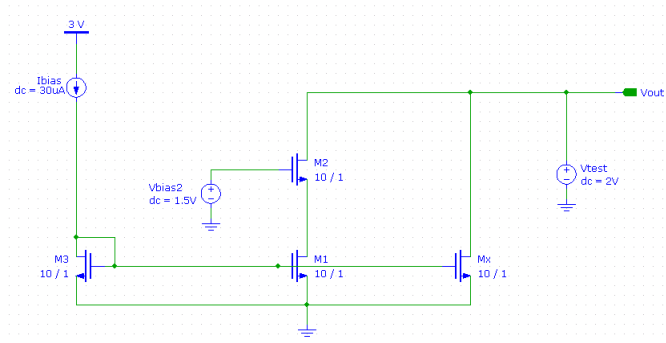


# Noise

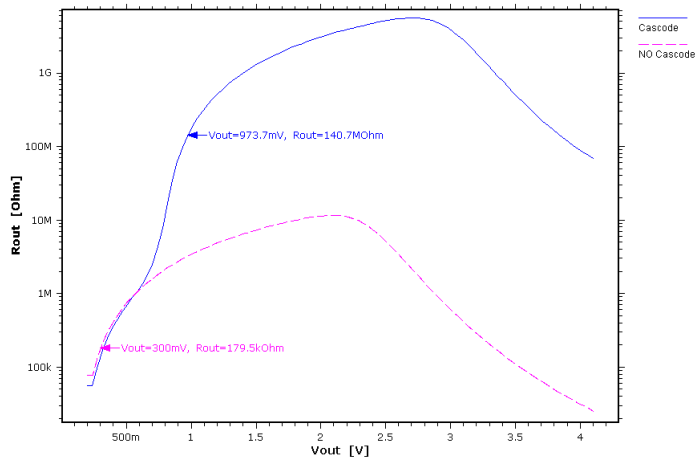
- Current source
  - Active
  - Passive
- Mirror
- Reference generator



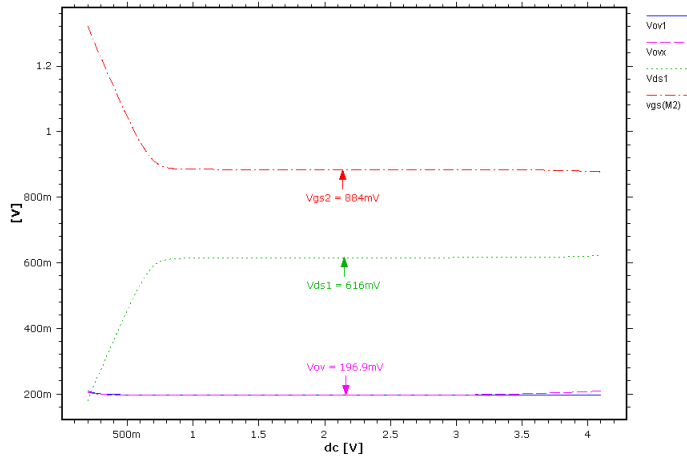
# Cascoding



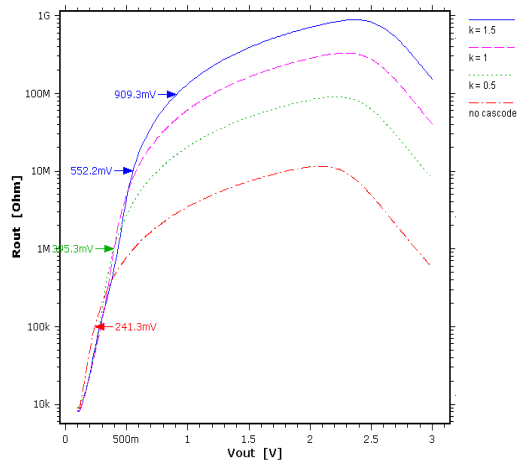
# Output Resistance



# Bias



$$R_{out} = f(k)$$

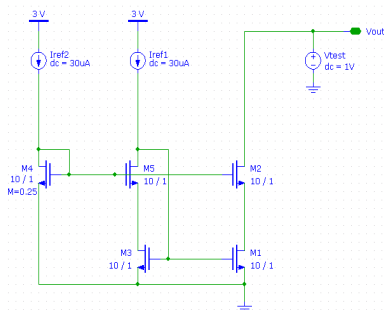


# High-Swing Cascode Biasing

- $V_{\min}$  versus  $R_{\text{out}}$  tradeoff is very steep
  - $V_{\min} > 2V_{\text{ov}}$  for cascode to be advantageous
- Goal: Set  $V_{\text{bias}}$  such that  $V_{\text{DS1}} \approx kV_{\text{ov}}$ 
  - $k > 1$  (typical: 1.3 ... 2)
  - Important for high  $R_{\text{out}}$
  - No penalty for moderate  $R_{\text{out}}$
- Design for insensitivity to
  - Process variations ( $\mu$ ,  $C_{\text{ox}}$ ,  $V_{\text{TH}}$ ,  $\gamma$ , ...)
  - Reference current  $I_{\text{ref}}$



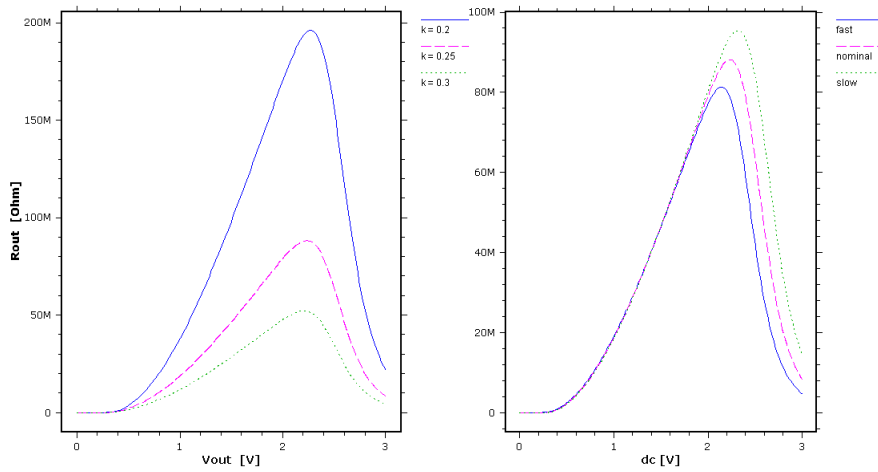
# High-Swing Bias 1



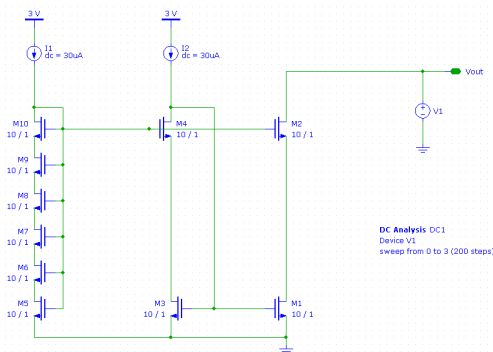
- $M_4$  quarter size or less (1/5 for high  $R_{\text{out}}$ )
- $M_5$  sets  $V_{\text{DS3}} = V_{\text{DS1}}$ : improves matching
- Sensitive to body-effect
- $L_{\text{current-source}} = L_{\text{cascode}}$
- Simple



# $R_{out}$



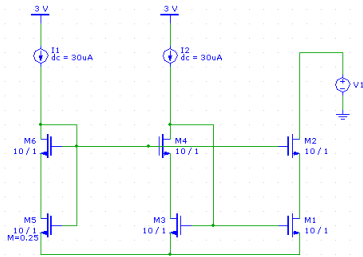
## High-Swing Bias 2



- M5 ... M10 replace quarter size device
- All devices same size
- Less sensitive to body-effect
- $L_{current-source} = L_{cascode}$



# High-Swing Bias 3



- $M_5$  in triode & smaller
- All other devices same size
- Sensitive to body-effect
- $L_{\text{current-source}} = L_{\text{cascode}}$



# Device Sizing

Objective:

$$V_{DS5} = K \times V_{d1}^{sat}$$

Square-law:

$$I_{D5} = \mu C_{ox} m_5 \frac{W}{L} (V_{GS5} - V_{TH5} - \frac{V_{DS5}}{2}) V_{DS5}$$

$$I_{D6} = \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{GS6} - V_{TH6})^2$$

with

$$I_{D5} = I_{D6}$$

$$V_{GS5} = V_{GS6} + V_{DS5}$$

$$V_{GS6} = V_{TH6} + V_{d6}^{sat} \quad \text{with} \quad V_{d6}^{sat} = V_{d1}^{sat}$$

substitute

$$(V_{d6}^{sat})^2 = m_5 (V_{DS5} + 2V_{d6}^{sat} + 2\Delta V_{TH}) V_{DS5}$$

solve:

$$V_{d6}^{sat} = m_5 V_{DS5} \left( 1 + \sqrt{1 + \frac{1}{m_5} + \frac{2\Delta V_{TH}}{m_5 V_{DS5}}} \right)$$

$$K = \frac{1}{m_5 \left( 1 + \sqrt{1 + \frac{1}{m_5} + \frac{2\Delta V_{TH}}{m_5 V_{DS5}}} \right)}$$

Examples:

$$m_5 = 1/3, \quad \Delta V_{TH} = 0V$$

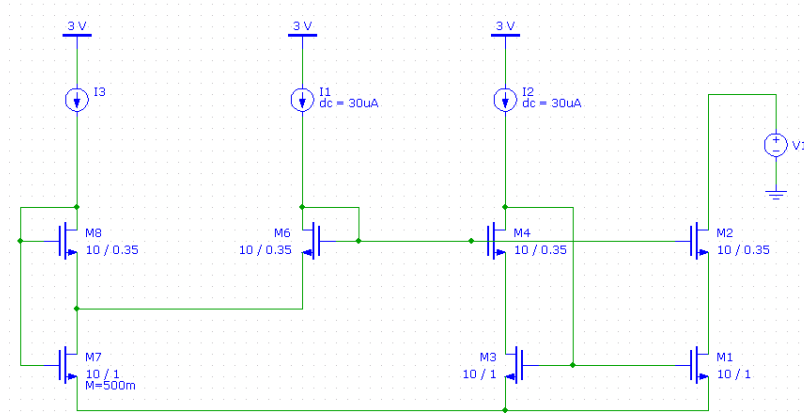
$$K = 1$$

$$m_5 = 1/4, \quad \Delta V_{TH} = 0V$$

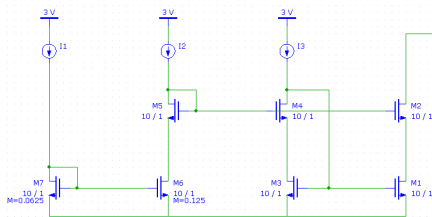
$$K = 1.55$$



# Different Device Length



# High-Swing Bias 4



$$I_{D7} = \frac{1}{2} \mu C_{ox} \left(\frac{W}{L}\right)_7 (V_{d7}^{sat})^2$$

$$I_{D6} = \mu C_{ox} \left(\frac{W}{L}\right)_6 (V_{d7}^{sat} - \frac{1}{2} V_{DS6}) V_{DS6}$$

solve :

$$V_{DS6} = V_{d7}^{sat} [1 - \sqrt{1-m}] \quad \text{with} \quad m = \frac{(W/L)_7}{(W/L)_6}$$

e.g. :

$$(W/L)_7 = 1/16 \quad \text{for} \quad V_{d7}^{sat} = 4V_{d1}^{sat}$$

$$(W/L)_6 = 1/8 \quad m = 0.5$$

then

$$V_{DS6} = 0.3V_{d7}^{sat} = 1.2V_{d1}^{sat}$$

- $M_6$  in triode
- Insensitive to body effect
- Large device ratios
- Need 3 reference sources (increased power dissipation)

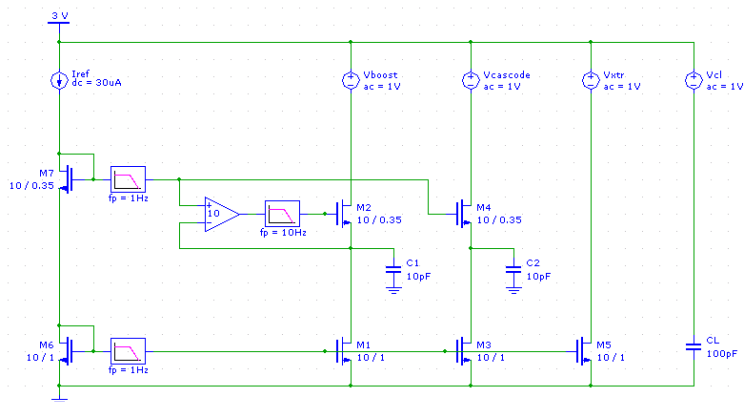


# Gain Boosting

- Use feedback to further increase  $R_{out}$ 
  - No increase of  $V_{min}$   
(unlike double cascode)
- Local feedback  $\rightarrow$  potential instability
- Beware of doublets (slow settling)
- Noise enhancement



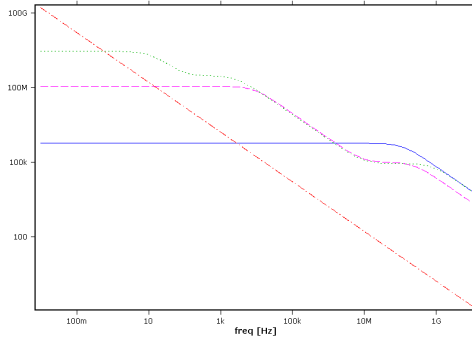
# Gain Boosting Analysis



**Note:** C2 would not be present in an actual circuit (or smaller). It is added here to separate pole frequencies.



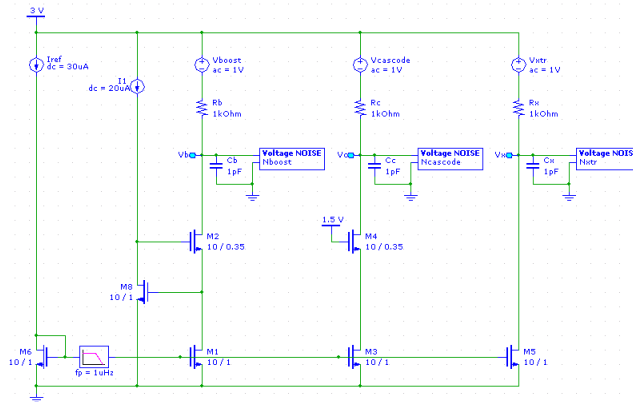
# Z<sub>out</sub>



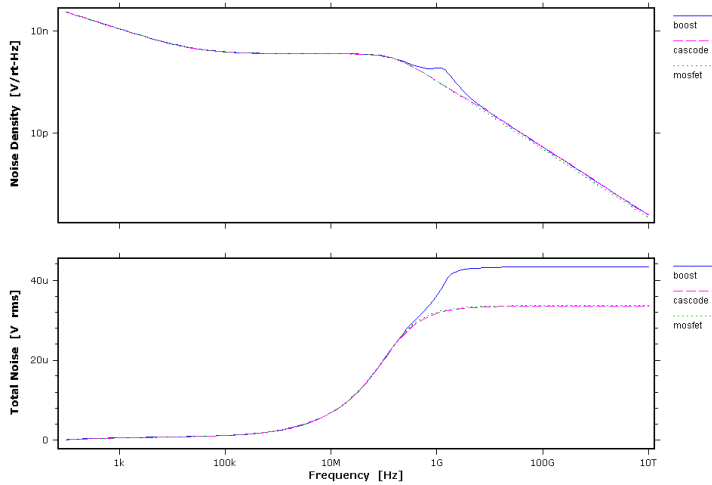
- $Z_{total} = Z_{boost} // Z_{CL}$
- Doublets  $\rightarrow$  slow settling
- Booster bandwidth tradeoff:
  - push doubled above closed-loop bandwidth
  - ensure stability (nondominant pole at source of  $M_2$ )



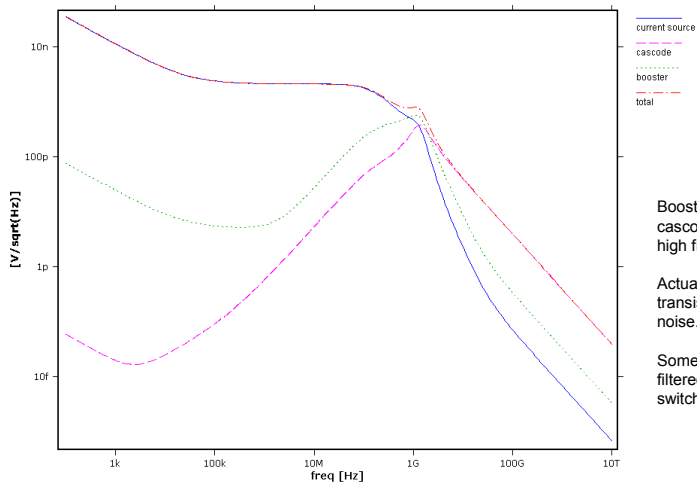
# Noise Analysis



# Noise Summary



# Noise Detail



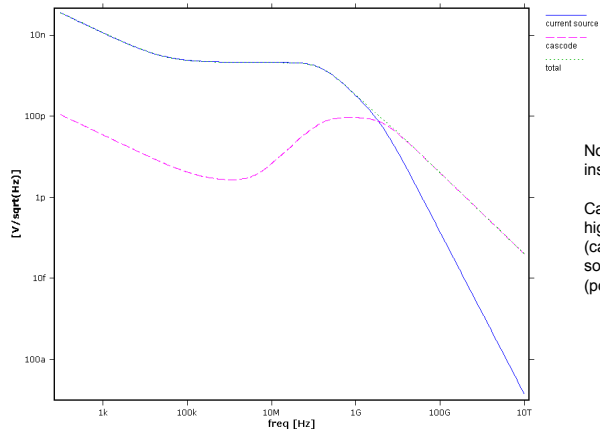
Booster amplifier and cascode contribute noise at high frequency.

Actual boosters have more transistors → additional noise.

Some noise might be filtered out by sampling switch.



# Cascode Noise



Noise from cascode usually insignificant.

Can contribute substantially at high frequency with lots of (capacitive) degeneration at the source of the cascode transistor (poor layout).

